Special Issue

Research on Image Analysis and Computer Vision

Message from the Guest Editors

Image analysis and computer vision mainly focuses on processing, analyzing and understanding digital images. In the context of large models with big data, establishing novel models, and exploring the underlying mechanisms of images and vision have been becoming the research focus in this field. This Special Issue aims at the latest and full-length research in the areas of image analysis and computer vision. Particularly, this Special Issue focuses on low-/high-level tasks of image analysis and vision. Containing multi-level research, this Special Issue is expected to bring comprehensive advances in the field of image analysis and computer vision. Topics of interest include but are not limited to the following points: 1. General image analysis, such as classification, super-resolution, visualization, etc. 2. Remote sensing image analysis, such as spectral unmixing, pansharpening, fusion, etc. 3. Combining of traditional methods and deep learning for image analysis and vision tasks. 4. Multi-modality image analysis and computer vision. 5. Unsupervised, generative, transfer learning models.

Guest Editors

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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